

# Formation and general characterization of a previously unknown ytterbium silicate (A-type $\text{Yb}_2\text{SiO}_5$ )

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On non-isothermal oxidation of ytterbium nitrogen wöhlerite ( $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ ), also known as the J-phase, a previously unknown and possibly metastable modification of  $\text{Yb}_2\text{SiO}_5$  was detected. It is isostructural with the A-type  $\text{RE}_2\text{SiO}_5$  modifications (RE = rare-earth element). The crystallographic data and stability of this new modification of  $\text{Yb}_2\text{SiO}_5$  are discussed and compared with available data on  $\text{RE}_2\text{SiO}_5$  compounds. The present results suggest that, in general, oxidation of rare-earth oxynitride phases might prove to be a fruitful method to obtain phases that are metastable or cannot be prepared by standard methods since their low-temperature stability range would require unrealistically long firing periods.

## 1. Introduction

Rare-earth silicates (e.g.  $\text{RE}_2\text{SiO}_5$  and  $\text{RE}_2\text{Si}_2\text{O}_7$ ) and oxynitrides (e.g.,  $\text{RE}_4\text{Si}_2\text{O}_7\text{N}_2$  and  $\text{RE}_2\text{Si}_3\text{O}_3\text{N}_4$ ) are important secondary phases commonly observed in  $\text{Si}_3\text{N}_4$  and SiC high-performance ceramics sintered with rare-earth oxides as sintering additives. The present authors are currently investigating the physico-chemical properties of members of the solid-solution series  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ – $\text{Yb}_4\text{Al}_2\text{O}_9$  [1]. On studying the oxidation of ytterbium nitrogen wöhlerite ( $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ ) (also known as the J-phase), a rather complex oxidation behaviour was observed. A previously unknown and possibly metastable low-temperature  $\text{Yb}_2\text{SiO}_5$  modification was observed during an intermediate oxidation stage. The present paper will give a crystallographic characterization of this remarkable phase. Its stability will be discussed in comparison with available data on the other known  $\text{RE}_2\text{SiO}_5$  modifications.

Further and more detailed results on the synthesis, some properties, oxidation behaviour and decomposition temperatures of  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$  and  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ – $\text{Yb}_4\text{Al}_2\text{O}_9$  solid solutions will be published elsewhere [1, 2].

## 2. Experimental procedure

Ytterbium nitrogen wöhlerite ( $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ ) was prepared by sintering stoichiometric mixtures of isotatically pressed powder blends of  $\text{Yb}_2\text{O}_3$  (99.5% purity; Ventron, Germany), amorphous  $\text{SiO}_2$  (Aerosil

2000; greater than 99.8% purity; Degussa, Germany) and  $\text{Si}_3\text{N}_4$  (greater than 98%  $\alpha$ - $\text{Si}_3\text{N}_4$ ; DP 14/13, Starck, Germany). X-ray powder diffraction (XRD) and scanning electron microscopy (SEM) showed the sintered wöhlerite samples to be single phase. The residual porosity amounted to about 10%. Rectangular samples with the dimensions 3 mm  $\times$  3 mm  $\times$  7 mm were diamond cut from a sintered bar and their oxidation behaviour was investigated by simultaneous thermal analysis (STA) (Netzsch, Germany model STA 409 with an upper temperature limit of about 1500 °C) in air using alumina crucibles. The STA samples had a mass of about 500 mg. Since preliminary differential thermal analysis (DTA) runs showed that active oxidation has already occurred below 700 °C, a heating rate of 2 K min<sup>-1</sup> from room temperature to 1500 °C was used. After being held at 1500 °C for 5 h, the samples were cooled to room temperature at the rate of 10 K min<sup>-1</sup>. Chemical analyses of the oxidation products at different oxidation stages were performed by carrier-gas hot extraction (N and O) and fluor combustion–Fourier transform infrared spectroscopy (Si), the latter being based on an analysis scheme developed at the present authors' institute. Pure  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$  was taken as a standard. Oxidation products were identified by XRD (Siemens D5000 X-ray powder diffractometer with position-sensitive detector; Ni-filtered Cu K $\alpha$  radiation) in the 2 $\theta$  range from 10 to 80°. For unit-cell parameter refinement, 99.999% pure silicon was added as internal standard.

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### 3. Results and discussion

#### 3.1. Oxidation products of $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$

Fig. 1 shows the results of a STA measurement in air. The DTA and thermogravimetry (TG) curves illustrate that the oxidation of ytterbium nitrogen woeherite ( $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ ) proceeds in (at least) three steps.

Oxidation starts at around  $575 \pm 10^\circ\text{C}$  (onset temperature). A weight gain is observed which is accompanied by a large and broad exothermic DTA effect with an asymmetric shape. XRD analysis of the oxidation product quenched from temperatures slightly above this first DTA effect gave an X-ray pattern similar to that of unoxidized  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ , but characterized by broad and slightly shifted X-ray reflections (full width at half-maximum (FWHM),  $2\theta \approx 0.45\text{--}0.60^\circ$ ). This indicates some structural imperfections and/or inhomogeneities in the oxidation product. Chemical analysis shows that about 1.4 mass% nitrogen is retained in the structure, i.e. about half of the nitrogen has been lost when compared with unoxidized  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$  (which contains 3.15 mass% N).

A second, small and sharp DTA effect is observed at  $1025 \pm 5^\circ\text{C}$ . It is accompanied by a small weight loss which is attributed to loss of gaseous nitrogen. The X-ray pattern of the resulting oxidation product at this stage was found to be that of a previously unknown  $\text{Yb}_2\text{SiO}_5$  modification (A- $\text{Yb}_2\text{SiO}_5$  according to the rare-earth silicate nomenclature established by Felsche [3]) and, additionally, traces of partly oxidized  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ . The occurrence of A- $\text{Yb}_2\text{SiO}_5$ , its crystallography and possible metastability are discussed in more detail in Section 3.2.

The results of the chemical analysis of this intermediate silicate oxidation product indicates a further lowered nitrogen content (0.98 mass% N) which is consistent with the corresponding effect in the TG curve although the measured absolute nitrogen content is considered to be too high owing to unverified reasons such as oxidation gradients within the sample. It is considered implausible that some nitrogen is dissolved in ionic form in the structure of A- $\text{Yb}_2\text{SiO}_5$ . It is more probable that there is nitrogen retention in remnants of unoxidized or partly oxidized

$\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$  within the STA sample. The nitrogen may be present in ionic and/or molecular form. Similar processes of nitrogen retention have been reported for the yttrium oxynitride compound  $\text{Y}_{10}(\text{SiO}_4)_6\text{N}_2$  [4].

The formation of  $\text{Yb}_2\text{SiO}_5$  (and not that of the other known stable ytterbium silicate,  $\text{Yb}_2\text{Si}_2\text{O}_7$ ) on oxidation of  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$  was to be expected since the Yb-to-Si ratio is exactly maintained during the oxidation process.

The oxidation of  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$  (or, in general,  $\text{RE}_4\text{Si}_2\text{O}_7\text{N}_2$ ) may be discussed in terms of its structure which consists of either  $\text{Si}_2\text{O}_5\text{N}$  or  $\text{Si}_2\text{O}_6\text{N}$  ditetrahedral units with N ions occupying the bridging position [5, 6]. These units are interconnected by Yb- $\text{O}_n$  (RE- $\text{O}_n$ ) polyhedra. On oxidation the nitrogen ions in the units are oxidized and possibly retained as atomic or molecular nitrogen. With increasing temperature, they evaporate as nitrogen gas with a concomitant replacement of their positions by oxygen ions. This obviously induces a rearrangement of the resulting Si-O units, causing the formation of isolated  $\text{SiO}_4$  tetrahedra. As a result the structure of A- $\text{RE}_2\text{SiO}_5$  is formed. This structure is described by a three-dimensional network of isolated  $\text{SiO}_4$  tetrahedra, extra non-silicon-bonded oxygen and  $\text{RE}^{3+}$  ions [3, 7]. Although B- $\text{RE}_2\text{SiO}_5$  has a very similar but slightly less space-filling structure [3, 8], it may be concluded from our results that formation of A- $\text{RE}_2\text{SiO}_5$  is favoured during the second oxidation step, on account of stronger structural similarities between A- $\text{RE}_2\text{SiO}_5$  and (partly oxidized)  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ .

The third, very small and broad exothermic effect due to oxidation is observed only in the DTA curve at  $1150 \pm 15^\circ\text{C}$  (see Fig. 1). XRD of the corresponding reaction product showed this DTA effect to conform to a transformation reaction of the low-temperature modification A- $\text{Yb}_2\text{SiO}_5$  to the stable high-temperature modification B- $\text{Yb}_2\text{SiO}_5$ . The chemical composition of the oxidation product at this stage is characterized by a further lowered nitrogen content (0.86 mass% N). Again, this nitrogen content is tentatively attributed to some nitrogen retention in parts of the oxidized sample.

A fourth, very small and somewhat irregular exothermic effect seen in the DTA curve is related to a further loss of nitrogen, as several chemical analyses of small parts of the oxidation sample showed (the analyses detected traces of N up to about 0.3 mass% N). XRD showed that no further change in the oxidation product (B- $\text{Yb}_2\text{SiO}_5$ ) occurred after this fourth peak or after the holding period at  $1500^\circ\text{C}$ .

#### 3.2. Occurrence of A- $\text{Yb}_2\text{SiO}_5$

The detection of A- $\text{Yb}_2\text{SiO}_5$  as an intermediate oxidation product of  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$  requires a more thorough discussion of the two different modifications of  $\text{RE}_2\text{SiO}_5$  compounds, namely, A and B.

In the systems  $\text{RE}_2\text{O}_3\text{--SiO}_2$  (RE = La to Lu, including Y and Sc), the rare-earth silicate compound  $\text{RE}_2\text{SiO}_5$  (with mole ratio  $\text{RE}_2\text{O}_3\text{:SiO}_2 = 1\text{:}1$ ) is

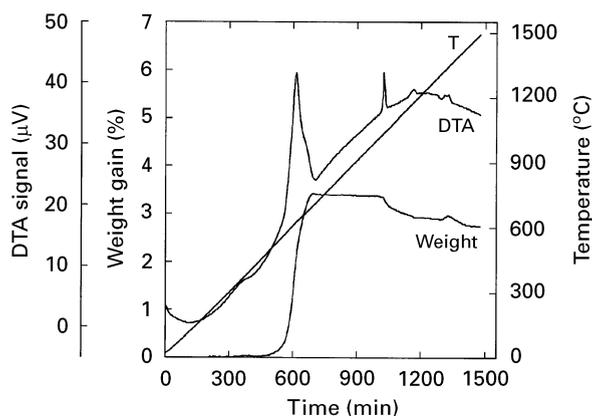


Figure 1 Result of STA measurement of the oxidation of  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ . Note the four exothermic effects in the DTA curve. For explanation see text.

a stable phase in all systems. Its melting point ranges between 1930 and 1980 °C. RE<sub>2</sub>SiO<sub>5</sub> forms two modifications designated A and B [3, 9–14]. A-RE<sub>2</sub>SiO<sub>5</sub> exists for large RE<sup>3+</sup> ions (RE = La to Tb) and is monoclinic (space group, *P2<sub>1</sub>/c*). B-RE<sub>2</sub>SiO<sub>5</sub> exists for small RE<sup>3+</sup> ions (RE = Tb to Lu, including Y and Sc) and is monoclinic as well (space group, *I2/a*; note that earlier space group designations *B2/b*, *B2/a*, *B2/c*, *C2/c* or *I2/c* are overruled by current nomenclature). Sc<sub>2</sub>SiO<sub>5</sub>, in contrary to what is stated by Leskelä and Jurkäs [15], also doubtlessly forms the B-type structure [12, 16, 17]. La<sub>2</sub>SiO<sub>5</sub> does not have an unknown structure, as suggested by Leskelä and co-workers [11, 18] but definitely forms the A-type modification [13]. A “third” RE<sub>2</sub>SiO<sub>5</sub> modification reported by Wanklyn *et al.* [19] for RE = Gd, Tb or Dy has unambiguously been demonstrated to be in fact the well-known A modification [14]. The misinterpretation of the respective X-ray diffractograms was shown to be caused by a strong preferred orientation effect of the X-ray samples due to the perfect cleavage of A-RE<sub>2</sub>SiO<sub>5</sub> parallel to {100} [9].

As seen from the above data, the “boundary” between the A and B modifications seems to be situated at RE = Tb. Felsche [3] states that A-Tb<sub>2</sub>SiO<sub>5</sub> is the stable modification. On the other hand, flux-grown B-Tb<sub>2</sub>SiO<sub>5</sub> is also known [20]. Gentner [13], on firing a stoichiometric mixture of terbium oxide and silica at 1200 °C in air, first obtained A-Tb<sub>2</sub>SiO<sub>5</sub> after a firing period of 30 days (including intermediate grinding); then, after firing for 40 days, a mixture of A- and B-Tb<sub>2</sub>SiO<sub>5</sub>, which subsequently transformed into single-phase B-Tb<sub>2</sub>SiO<sub>5</sub> after firing for 80 days. A report on the A modification for the small Dy<sup>3+</sup> ion by Anan’eva *et al.* [9] must be regarded with suspicion, since the sample of Anan’eva *et al.* was doped with 1–2 mass% Nd, thus presumably promoting a ionic size-related stabilization of the otherwise unstable A-Dy<sub>2</sub>SiO<sub>5</sub>.

Table I gives the measured X-ray powder data for A-Yb<sub>2</sub>SiO<sub>5</sub>. The X-ray pattern is similar to that of

TABLE I X-ray powder data for A-Yb<sub>2</sub>SiO<sub>5</sub><sup>a</sup>

A-Yb <sub>2</sub> SiO <sub>5</sub> (this work)			
$d_{\text{obs}}^{\text{b}}$ (Å)	$I_{\text{obs}}$	$hkl$	$d_{\text{calc}}$ (Å)
8.64	6	100	8.63
5.332	56	110	5.328
4.633	32	011	4.633
4.313	27	200	4.316
3.788	20	111	3.789
3.639	14	210	3.639
3.511	7	21 $\bar{1}$	3.515
3.274	31	10 $\bar{2}$	3.275
2.987	79	021	2.988
2.962	69	20 $\bar{2}$	2.960
2.877	65	300	2.877
2.748 (s)	54	10 $\bar{2}$	2.754
2.720	100	121	2.721
2.646 (s)	22	310	2.648
2.613	68	22 $\bar{1}$	2.614
2.331 (b)	4	31 $\bar{2}$	2.333
		221	2.325

TABLE I *Continued*

A-Yb <sub>2</sub> SiO <sub>5</sub> (this work)			
$d_{\text{obs}}^{\text{b}}$ (Å)	$I_{\text{obs}}$	$hkl$	$d_{\text{calc}}$ (Å)
2.216	4	32 $\bar{1}$	2.215
2.181	6	130	2.184
2.167	6	212	2.165
2.128	12	031	2.127
2.054 (b)	21	410	2.056
		40 $\bar{2}$	2.056
2.041	21	21 $\bar{3}$	2.039
2.026 (b)	11	131	2.024
		013	2.021
1.955	29	321	1.954
1.899 (b)	3	302	1.897
		31 $\bar{3}$	1.894
1.866 (s)	7	113	1.866
		42 $\bar{1}$	1.863
1.842 (b)	54	231	1.844
		12 $\bar{3}$	1.842
		032	1.840
1.789 (b)	14	23 $\bar{2}$	1.795
		33 $\bar{1}$	1.788
		023	1.776
1.729 (b)	10	51 $\bar{1}$	1.731
		500	1.726
1.702 (s)	11	32 $\bar{3}$	1.705
1.692 (b)	16	040	1.694
		123	1.684
1.667 (b)	15	33 $\bar{2}$	1.671
		51 $\bar{2}$	1.667
		140	1.661
1.641	6	331	1.642
		104	1.641
1.596 (b)	15	402	1.599
		114	1.595
1.583 (b)	19	141	1.588
		43 $\bar{1}$	1.587
		52 $\bar{1}$	1.583
1.572 (b)	17	240	1.576
		13 $\bar{3}$	1.574
1.563 (b)	16	24 $\bar{1}$	1.566
		423	1.564
		430	1.560
1.540 (b)	10	033	1.544
		223	1.540
		520	1.538
1.505 (bb)	4	51 $\bar{3}$	1.515
		14 $\bar{2}$	1.504
		241	1.496
1.468 (b)	13	133	1.472
		24 $\bar{2}$	1.470
		34 $\bar{1}$	1.466
1.455 (b)	14	114	1.458
		61 $\bar{1}$	1.456
		332	1.452
1.445 (b)	15	422	1.446
		414	1.446
		142	1.442

<sup>a</sup> Measured by XRD (Siemens D5000 with position-sensitive detector; Cu K $\alpha$  radiation; Si as internal standard). Indexing for space group *P2<sub>1</sub>/c*:  $a = 8.951(3)$  Å,  $b = 6.772(2)$  Å,  $c = 6.588(2)$  Å,  $\beta = 105.36(4)^\circ$  and  $V = 385.1(1)$  Å<sup>3</sup>.

<sup>b</sup>s, shoulder of adjacent stronger reflection; b, broad; bb, very broad.

(stable) A-Y<sub>2</sub>SiO<sub>5</sub> (also known as X<sub>1</sub>-Y<sub>2</sub>SiO<sub>5</sub> [12, 21]). The refined unit-cell parameters of A-Yb<sub>2</sub>SiO<sub>5</sub> are as follows:  $a = 8.951(3)$  Å,  $b = 6.772(2)$  Å,  $c = 6.588(2)$  Å,  $\beta = 105.36(4)^\circ$  and  $V = 385.1(1)$  Å<sup>3</sup>. Fig. 2 illustrates

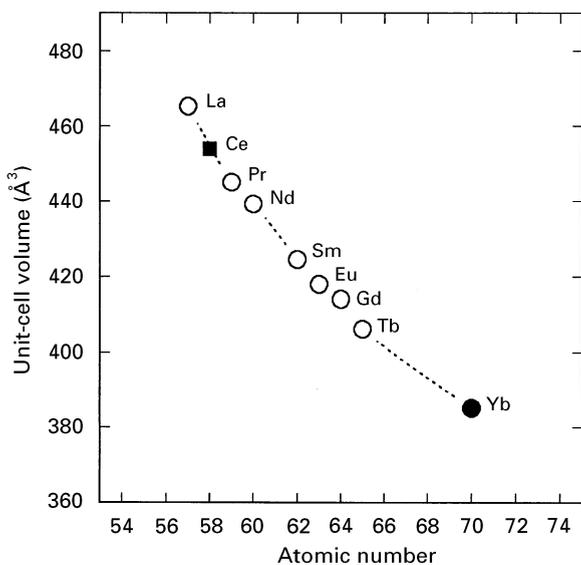


Figure 2 Unit-cell volume of A-type  $\text{RE}_2\text{SiO}_5$ , (○), from [3]; (■), from [22]; (●), from this work. The value for A- $\text{Yb}_2\text{SiO}_5$  measured in this work fits well into this series.

the relation between the A-type  $\text{RE}_2\text{SiO}_5$  unit-cell volume and the RE atomic number using the available literature data [3, 22] and the present results for A- $\text{Yb}_2\text{SiO}_5$ . One sees that the volume of A- $\text{Yb}_2\text{SiO}_5$  fits well into the series.

The thermodynamic stability of A- $\text{Yb}_2\text{SiO}_5$  is not clarified at the moment. The observation of this modification A- $\text{Yb}_2\text{SiO}_5$  in the temperature range between about 1025 and about 1150 °C may firstly indicate that it is a thermodynamically stable phase from room temperature up to its transformation temperature (about 1150 °C) where it transforms into the high-temperature modification B- $\text{Yb}_2\text{SiO}_5$ . On the other hand, A- $\text{Yb}_2\text{SiO}_5$  may represent a metastable phase whose genesis is related to its state as an oxidation product.

At the present stage of investigations, nothing specific is known about the long-term stability of A- $\text{Yb}_2\text{SiO}_5$  at temperatures below about 1150 °C. The observed transformation temperature may represent the thermodynamic transformation temperature. Kinetically induced shifts of the transformation temperature towards higher temperatures are considered improbable since the oxidation products are extremely fine grained and therefore highly reactive, and since the heating rate used was small (2 K min<sup>-1</sup>). Although the A–B transformation reaction might be reversible it would prove useless to verify this reversibility since all phase transformations in rare-earth silicates are of the reconstructive type and therefore extremely sluggish [3, 13, 14, 23, 24]. Long-term anneals in the temperature range between 900 and 1200 °C are planned to evaluate the thermodynamic stability of A- $\text{Yb}_2\text{SiO}_5$ .

$\text{Y}_2\text{SiO}_5$  is the only  $\text{RE}_2\text{SiO}_5$  compound that is definitely known to occur in both stable modifications A and B. The low-temperature phase A- $\text{Y}_2\text{SiO}_5$  on heating slowly transforms into the high-temperature phase B- $\text{Y}_2\text{SiO}_5$ ; the transformation temperature is roughly given as about 1190 °C [12, 21]. Since the

$\text{Yb}^{3+}$  ionic radius (0.868 Å [25]) is smaller than the  $\text{Y}^{3+}$  ionic radius (0.900 Å), any thermodynamically fixed transformation temperature of  $\text{Yb}_2\text{SiO}_5$  must be lower than that of  $\text{Y}_2\text{SiO}_5$ . The observed transformation temperature for  $\text{Yb}_2\text{SiO}_5$  (about 1150 °C) would support this assumption.

The present results illustrate that it may prove possible that A-type  $\text{RE}_2\text{SiO}_5$  modifications of Dy, Ho, Er, Tm and Lu, which probably all have temperature stability ranges below approximately 1250–1100 °C, may be prepared in a similar manner by oxidation of the respective  $\text{RE}_4\text{Si}_2\text{O}_7\text{N}_2$  compounds.

#### 4. Conclusions

On oxidation of  $\text{Yb}_4\text{Si}_2\text{O}_7\text{N}_2$ , a previously unknown modification of  $\text{Yb}_2\text{SiO}_5$  (A- $\text{Yb}_2\text{SiO}_5$ ) is formed as an intermediate oxidation product. Its crystallography, stability and relation to other  $\text{RE}_2\text{SiO}_5$  compounds are evaluated.

The results of our investigation lead to the general assumption that oxidation of oxynitride phases might prove to be a fruitful method to obtain phases and/or modifications that either are metastable or cannot be prepared as stable phases by standard methods since their low-temperature stability range would require unrealistically long firing periods. Structural similarities between oxynitrides and desired oxidation products may be used to prepare specific modifications.

For example, oxidation of nitrogen-containing members along the solid solution series  $\text{RE}_4\text{Si}_2\text{O}_7\text{N}_2$ – $\text{RE}_4\text{Al}_2\text{O}_9$  (with general formula  $\text{RE}_4\text{Si}_{2-x}\text{Al}_x\text{O}_{7+x}\text{N}_{2-x}$ ) [1] might be used to synthesize the nitrogen-free limited solid solution  $\text{RE}_4\text{Al}_{2(1-x)}\text{Si}_{2x}\text{O}_{9+x}$  which has been observed in the systems  $\text{RE}_2\text{O}_3$ – $\text{Al}_2\text{O}_3$ – $\text{SiO}_2$  for RE = Gd, Y or Yb [24, 26, 27].

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